

INTERNATIONAL STANDARD

**Electromagnetic compatibility (EMC) -
Part 4-30: Testing and measurement techniques - Power quality measurement
methods**



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**Electromagnetic compatibility (EMC) -
Part 4-30: Testing and measurement techniques -
Power quality measurement methods**

FOREWORD

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IEC 61000 4-30 has been prepared by subcommittee 77A: EMC – Low- frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility. It is an International Standard.

It forms part 4-30 of IEC 61000. It has the status of a basic EMC publication in accordance with IEC Guide 107.

This fourth edition cancels and replaces the third edition published in 2015. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) IEC 61000-4-30:2015/AMD1:2021 and IEC 61000-4-30:2015/COR1:2016 were included.
- b) The measurement method for rapid voltage changes (RVC) has been corrected and extended.
- c) The measurement method for voltage events has been updated and extended.
- d) Annex C was divided into 2 parts:
 - 1) Annex C: The measurement method from IEC 61000-4-7:2002 and IEC 61000-4-7:2002/AMD1:2008, Annex B for conducted emissions in the 2 kHz to 9 kHz range has been separated.
 - 2) Annex D: A new measurement method for conducted emissions in the 9 kHz to 150 kHz range has been added.
- e) Annex D (underdeviation and overdeviation parameters) was removed.
- f) Annex E (Class B) was removed.

The text of this International Standard is based on the following documents:

Draft	Report on voting
77A/1253/FDIS	77A/1268/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

A list of all parts in the IEC 61000 series, published under the general title *Electromagnetic compatibility (EMC)*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn, or
- revised.

INTRODUCTION

IEC 61000 is published in separate parts according to the following structure:

Part 1: General

- General considerations (introduction, fundamental principles)
- Definitions, terminology

Part 2: Environment

- Description of the environment
- Classification of the environment
- Compatibility levels

Part 3: Limits

- Emission limits
- Immunity limits (in so far as they do not fall under the responsibility of the product committees)

Part 4: Testing and measurement techniques

- Measurement techniques
- Testing techniques

Part 5: Installation and mitigation guidelines

- Installation guidelines
- Mitigation methods and devices

Part 6: Generic standards

Part 9: Miscellaneous

Each part is further subdivided into several parts, published either as International Standards or as Technical Specifications or Technical Reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and completed by a second number identifying the subdivision (example: IEC 61000-6-1).

1 Scope

This part of IEC 61000-4 defines the methods for measurement and interpretation of results for power quality parameters in AC power supply systems with a declared fundamental frequency of 50 Hz or 60 Hz.

Measurement methods are described for each relevant parameter in terms that give reliable and repeatable results, regardless of the method's implementation. This document addresses measurement methods for in-situ measurements.

This document covers two classes of measurement methods (Class A and Class S). The classes of measurement are specified in Clause 4.

NOTE 1 In this document, "A" stands for "advanced" and "S" stands for "surveys".

Measurement of parameters covered by this document is limited to conducted phenomena in power systems. The power quality parameters considered in this document are power frequency, magnitude of the supply voltage, flicker, supply voltage dips and swells, voltage interruptions, transient voltages, supply voltage unbalance, voltage harmonics and interharmonics, rapid voltage changes, mains communicating system (MCS) voltages, magnitude of current, harmonic currents, interharmonic currents and current unbalance.

Emissions in the 2 kHz to 150 kHz range are considered in Annex C and Annex D.

Depending on the purpose of the measurement, all or a subset of the phenomena on this list can be measured.

NOTE 2 Test methods for verifying compliance with this document can be found in IEC 62586-2.

NOTE 3 The effects of transducers inserted between the power system and the instrument are acknowledged but not addressed in detail in this document. Guidance about effects of transducers can be found IEC TR 61869-103.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-161:1990, *International Electrotechnical Vocabulary (IEV) - Part 161: Electromagnetic compatibility*

IEC 60050-161:1990/AMD9:2019

IEC 61000-2-4:2024, *Electromagnetic compatibility (EMC) - Part 2-4: Environment - Compatibility levels in power distribution systems in industrial locations for low-frequency conducted disturbances*

IEC 61000-4-7:2002, *Electromagnetic compatibility (EMC) - Part 4-7: Testing and measurement techniques - General guide on harmonics and interharmonics measurements and instrumentation, for power supply systems and equipment connected thereto*
IEC 61000-4-7:2002/AMD1:2008

IEC 61000-4-15:2010, *Electromagnetic compatibility (EMC) - Part 4-15: Testing and measurement techniques - Flickermeter - Functional and design specifications*

IEC 62586-2, *Power quality measurement in power supply systems - Part 2: Functional tests and uncertainty requirements*